

Materials Technical Advisory Committee
National Medal of Technology
Nomination Evaluation Committee
National Technical Information Service
Advisory Board
Regulations and Procedures Technical
Advisory Committee
Sensors Technical Advisory Committee
Subcommittee on Export
Administration, President's Export
Council
Telecommunications Equipment
Technical Advisory Committee
Transportation and Related Equipment
Technical Advisory Committee
U.S. Automotive Parts Advisory
Committee
Visiting Committee on Advanced
Technology

FOR FURTHER INFORMATION CONTACT:

Victoria A. Kurk, Management Analyst,
Office of the Secretary, Department of
Commerce, Washington, DC 20230,
Telephone (202) 482-4115.

Dated: September 18, 1995.

Victoria A. Kruk,

Office of Executive Assistance Management.

[FR Doc. 95-23654 Filed 9-22-95; 8:45 am]

BILLING CODE 3510-FA-M

National Institute of Standards and Technology

Government Owned Inventions

AGENCY: National Institute of Standards and Technology, Commerce.

ACTION: Notice of Government owned inventions available for licensing.

SUMMARY: The inventions listed below are owned by the U.S. Government, as represented by the Department of Commerce, and are available for licensing in accordance with 35 U.S.C. 207 and 37 CFR Part 404 to achieve expeditious commercialization of results of federally funded research and development.

FOR FURTHER INFORMATION CONTACT:

Technical and licensing information on these inventions may be obtained by writing to: Marcia Salkeld, National Institute of Standards and Technology, Office of Technology Partnerships, Physics Building, Room B-256, Gaithersburg, MD 20899; Fax 301-869-2751. Any request for information should include the NIST Docket No. and Title for the relevant invention as indicated below.

SUPPLEMENTARY INFORMATION: The inventions available for licensing are:

NIST Docket No. 94-031

Title: Friction and Wear Resistant Coatings For Titanium and Its Alloys.

Description: This NIST invention is a method to control friction and wear of titanium and its alloys through the use of novel coatings. The coatings contain epoxide polymers with anti-wear fillers.

NIST Docket No. 95-034CIP

Title: Overlay Target and Measurement Procedure to Enable Self-Correction for Wafer-Induced and Tool-Induced Shift by All-Imaging-Sensor Means.

Description: The estimates of overlay extracted by a metrology instrument from standard targets on IC wafers are ordinarily burdened by difficult-to-estimate systematic errors called shifts. The first of two parts of this invention is to replacement of a standard overlay target used in normal IC fabrication practice with multiple instances of a so-called target unit. The referenced target units constitute a single so-called self-calibrating optical-overlay target structure. Each target unit is a standard target having an additional grouping of features called a null-detector subsystem. The null-detector subsystems embodied in the new self-calibrating optical-overlay target structure enable the extraction of zero-overlay indices. The second part of the invention includes modification to the metrology instrument's target scanning and imaging systems to provide supplementary inspection of the null-detector subsystems. The zero-overlay indices, when analyzed in conjunction with the burdened overlay estimates extracted from the corresponding multiple instances of the standard targets within the same self-calibrating optical-overlay target structure, enable an estimate of the shift affecting the overlay measurements. The unique novelty of providing self-calibration of the metrology instrument, with respect to shift, on the same substrate as that from which overlay estimates are sought by the user has significant commercial importance.

Dated: September 15, 1995.

Samuel Kramer,

Associate Director.

[FR Doc. 95-23639 Filed 9-22-95; 8:45 am]

BILLING CODE 3510-13-M

National Oceanic And Atmospheric Administration

Open Meeting Florida Keys National Marine Sanctuary Advisory Committee

AGENCY: Sanctuaries and Reserves Division (SRD), Office of Ocean and Coastal Resource Management (OCRM), National Ocean Service (NOS), National Oceanic and Atmospheric

Administration (NOAA), Department of Commerce.

ACTION: Florida Keys National Marine Sanctuary Advisory Council (SAC) notice of open meeting.

SUMMARY: The Council was established in December 1991 to advise and assist the Secretary of Commerce in the development and implementation of the comprehensive management plan for the Florida Keys National Marine Sanctuary.

TIME AND PLACE: October 5, 1995, from 8:30 a.m. until noon. The meeting location will be at the Monroe County Government Center, 2796 Overseas Highway, Marathon, Florida.

AGENDA: Updates on the ten SAC action plan working groups.

PUBLIC PARTICIPATION: The meeting will be open to public participation. Public comment will be received from 11:30 until noon. Seats will be set aside for the public and the media. Seats will be available on a first-come first-served basis.

FOR FURTHER INFORMATION CONTACT:

June Cradick at (305) 743-2437.

Dated: September 19, 1995.

(Federal Domestic Assistance Catalog Number 11.429 Marine Sanctuary Program)
David L. Evans,

Acting Assistant Administrator for Ocean Services and Coastal Zone Management.

[FR Doc. 95-23722 Filed 9-22-95; 8:45 am]

BILLING CODE 3510-08-M

DEPARTMENT OF DEFENSE

Office of the Secretary

Defense Policy Board Advisory Committee

ACTION: Notice of Advisory Committee meeting.

SUMMARY: The Defense Policy Board Advisory Committee will meet in closed session on 3-4 October 1995 from 0800 until 1700 in the Pentagon, Washington, DC.

The mission of the Defense Policy Board is to provide the Secretary of Defense, Deputy Secretary of Defense and the Under Secretary of Defense for Policy with independent, informed advice and opinion concerning major matters of defense policy. At this meeting the Board will hold classified discussions on national security matters.

In accordance with Section 10(d) of the Federal Advisory Committee Act, Public Law No. 92-463, as amended [5 U.S.C. App. II (1982)], it has been